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(12) **United States Design Patent**  
**Oonuma et al.**

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(54) **ELECTRON MICROSCOPE**

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(\*\*) Term: **14 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (9) Cl.** ..... **16-06**

(52) **U.S. Cl.** ..... **D16/131**

(58) **Field of Classification Search** ..... D16/131;  
250/311; 359/383, 384, 385, 389, 390, 368,  
359/370, 371, 372; D24/185, 232, 234; D10/81;  
D6/396; D23/286; 312/209  
See application file for complete search history.

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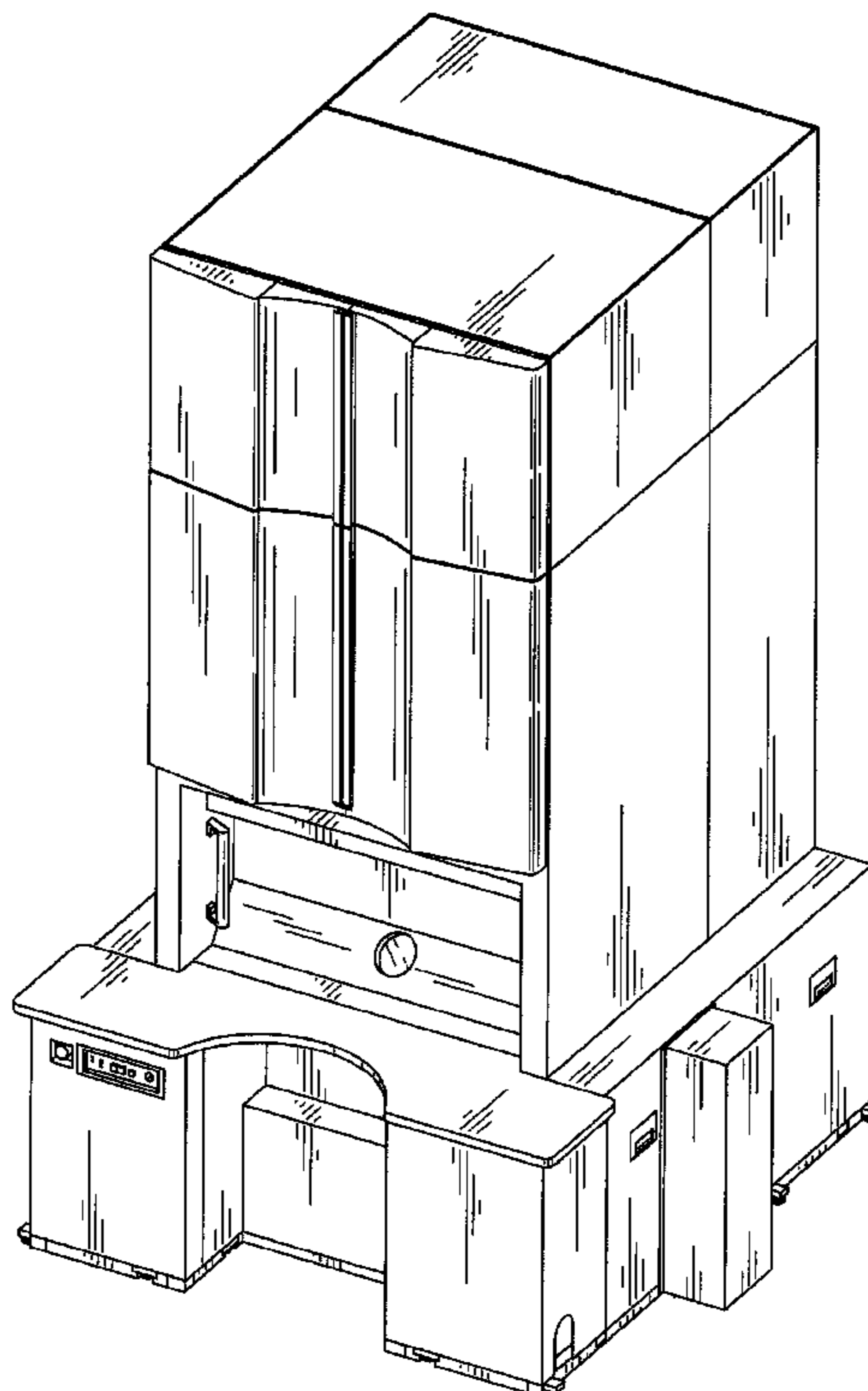
(57) **CLAIM**

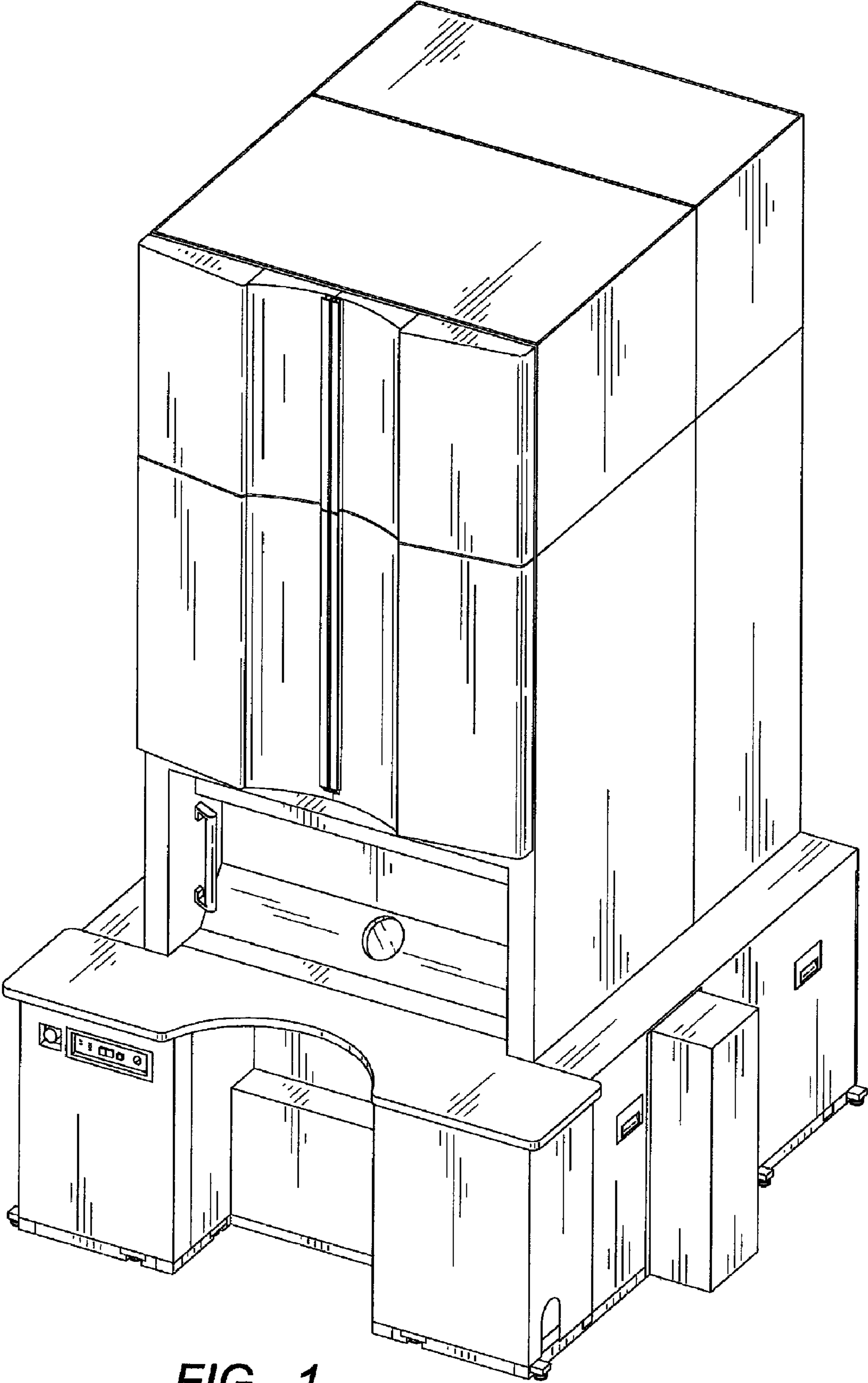
We claim the ornamental design for an electron microscope, as shown and described.

**DESCRIPTION**

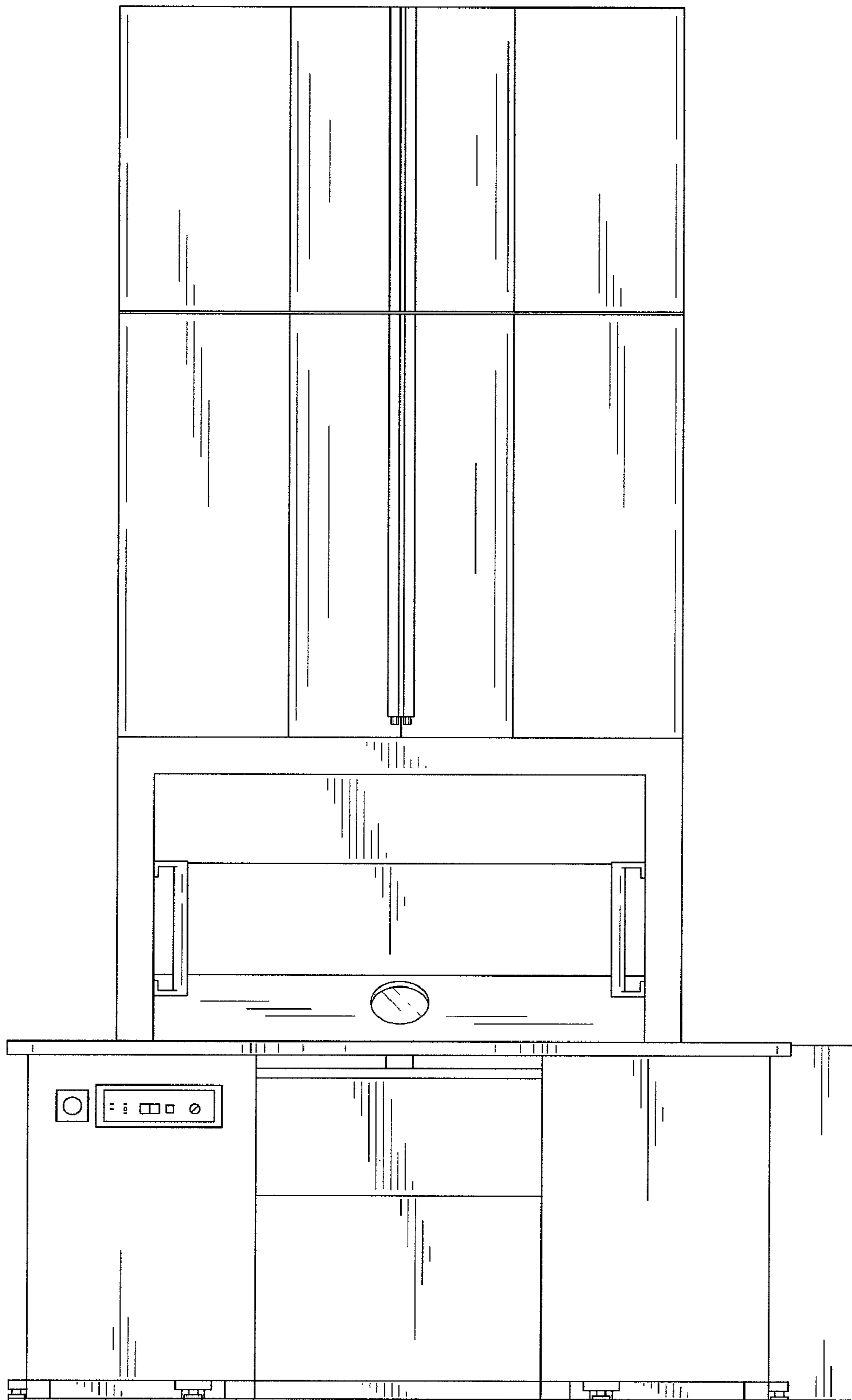
FIG. 1 is a front, top and right side perspective view of an electron microscope showing our new design;  
FIG. 2 is a front elevational view thereof;  
FIG. 3 is a rear elevational view thereof;  
FIG. 4 is a top plan view thereof;  
FIG. 5 is a bottom plan view thereof;  
FIG. 6 is a left side elevational view thereof; and,  
FIG. 7 is a right side elevational view thereof.  
The broken lines shown are for illustrative purpose and form no part of the claimed design.

**1 Claim, 7 Drawing Sheets**

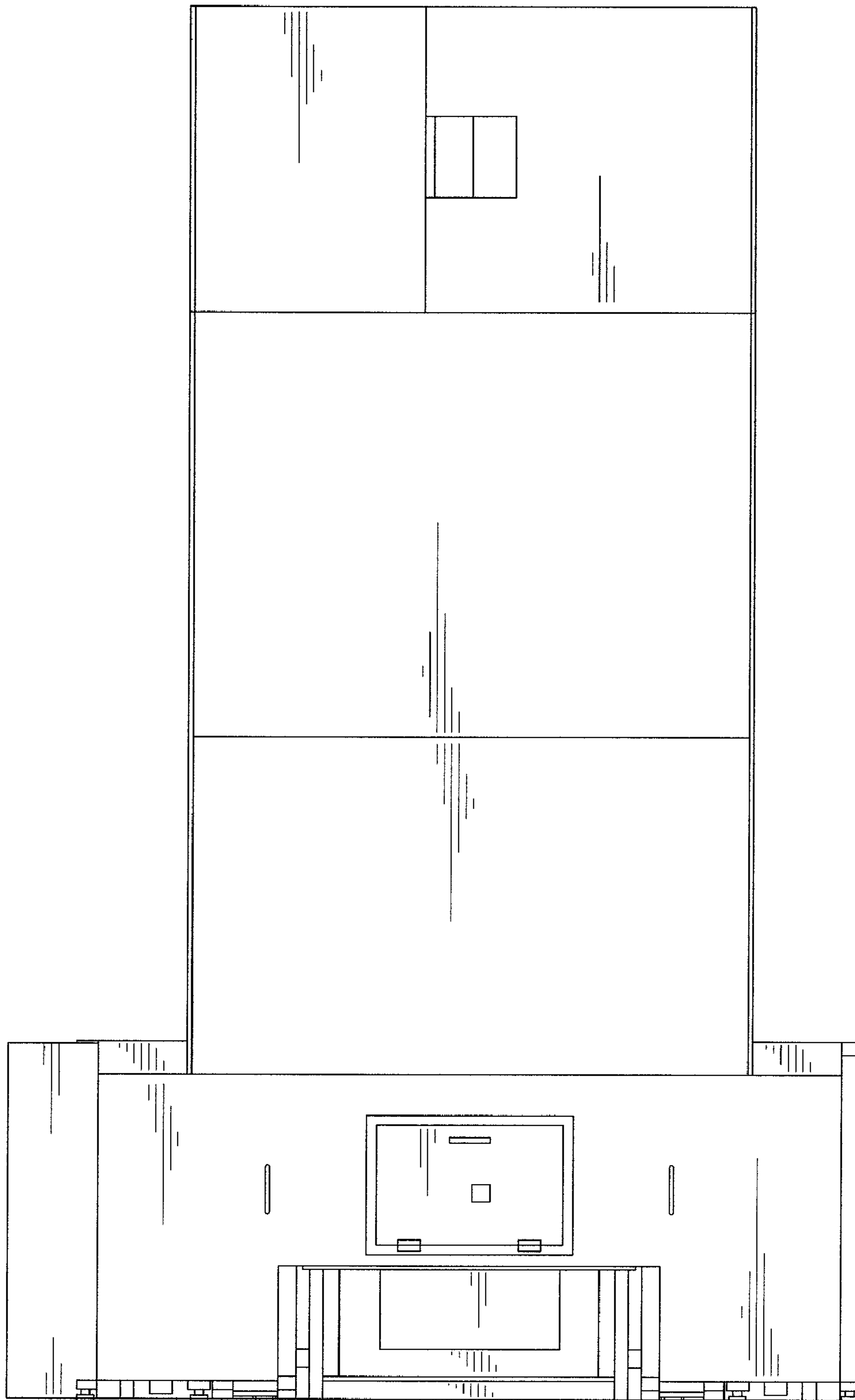




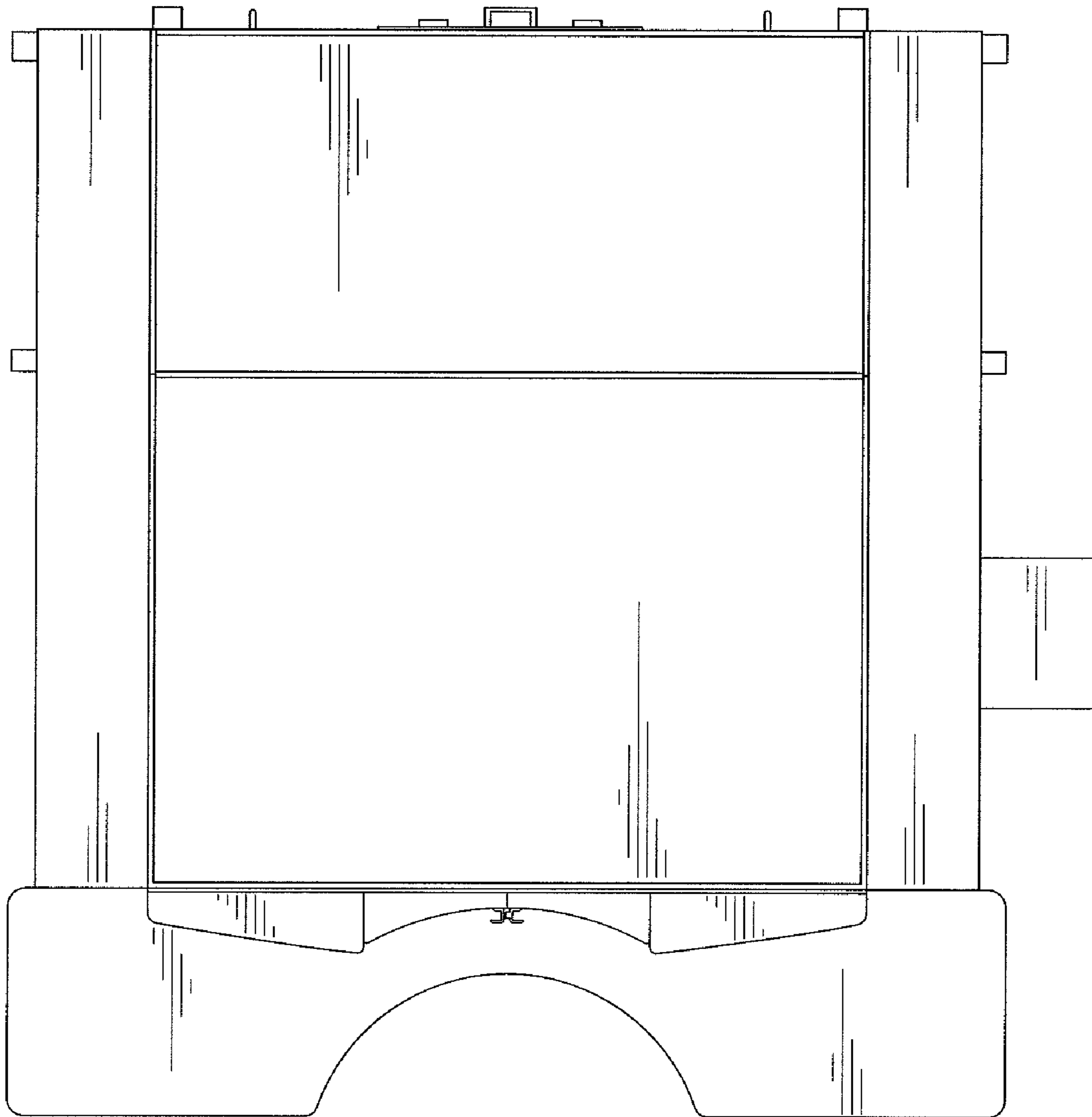
**FIG. 1**



**FIG. 2**



**FIG. 3**



**FIG. 4**

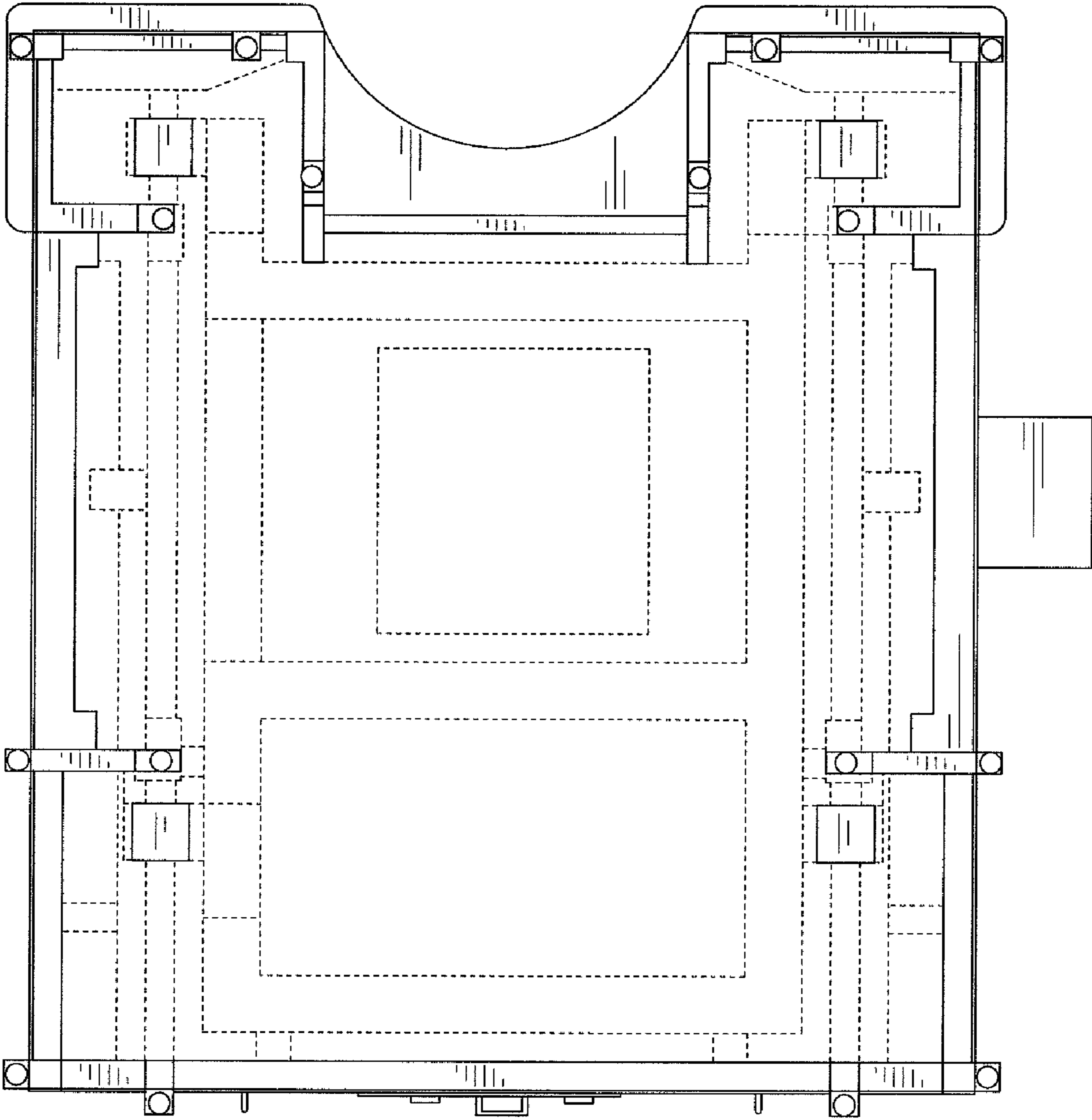
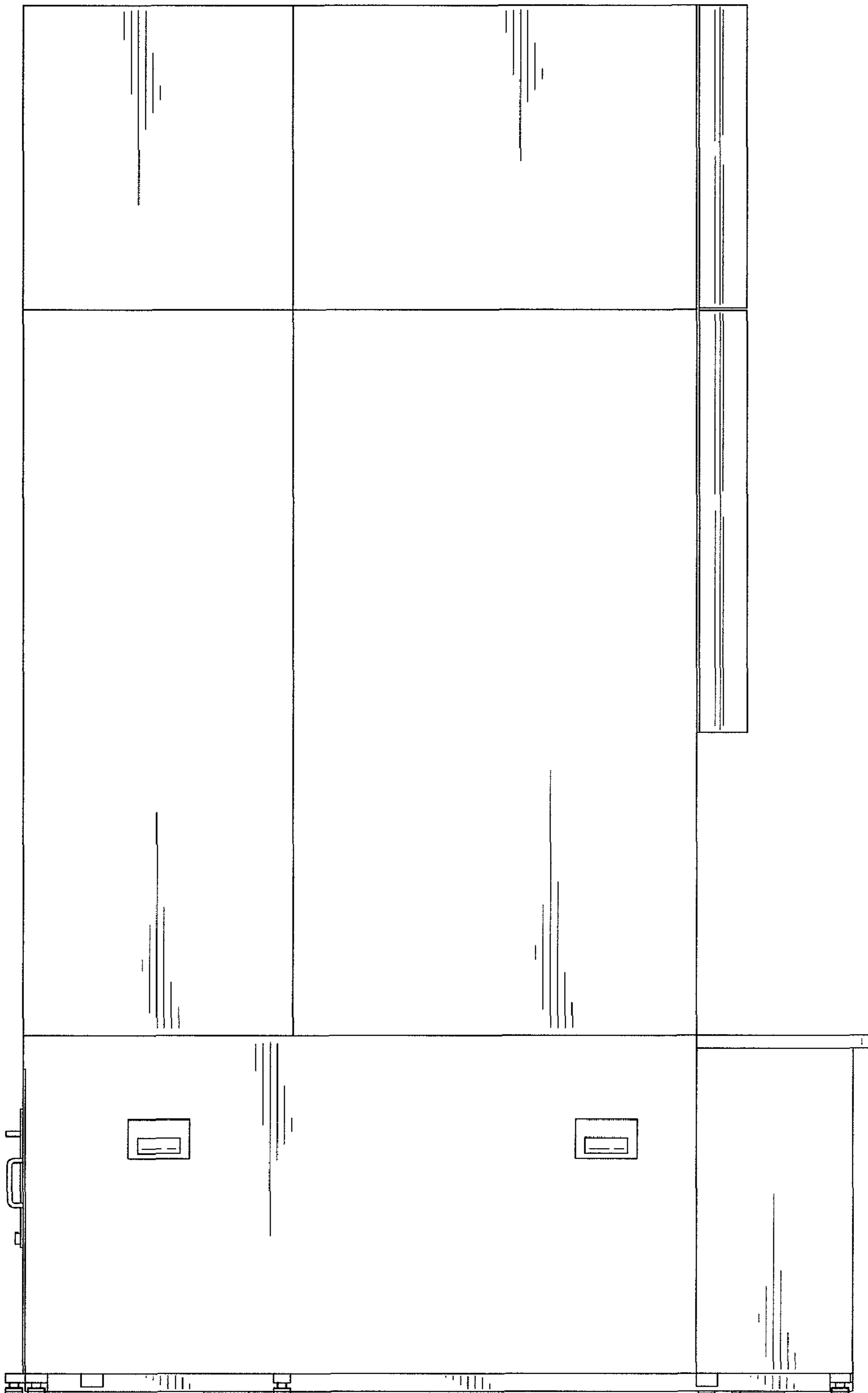


FIG. 5



**FIG. 6**

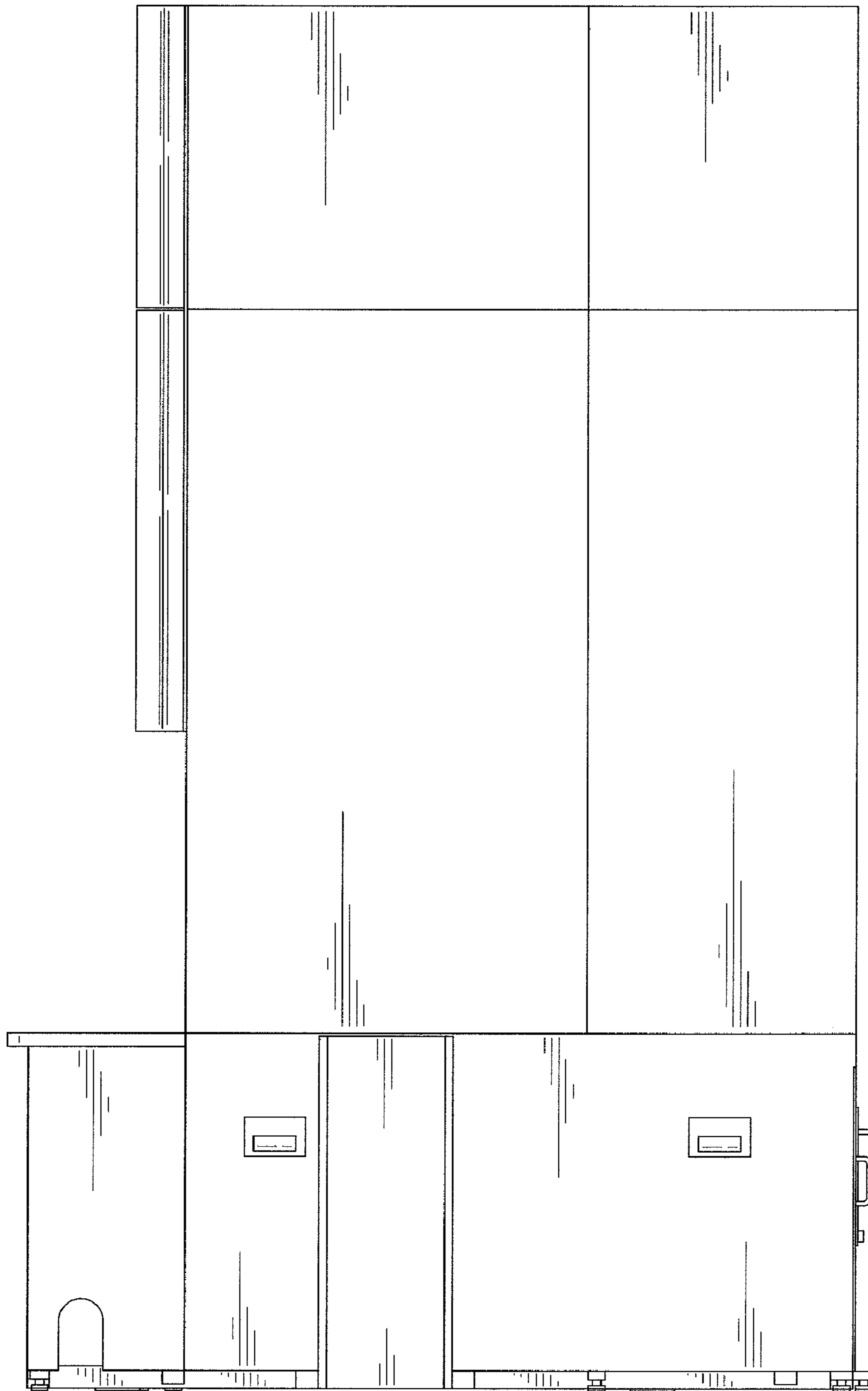


FIG. 7